## Application/Control No. 10/041,613 Applicant(s)/Patent Under Reexamination CHO ET AL. Examiner HANH NGUYEN Applicant(s)/Patent Under Reexamination CHO ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

			Date		01
*		Document Number Country Code-Number-Kind Code	MM-YYYY	Name	Classification
	Α	US-4,777,394	10-1988	Hayashi, Katsuhiko	310/156.08
	В	US-4,162,418	07-1979	Kawaki et al.	310/163
	С	US-6,271,638	08-2001	Erdman et al.	318/439
	D	US-4,528,533	07-1985	Montagu, Jean I.	310/49R
	E	US-6,262,510	07-2001	Lungu, lancu	310/166
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					,
	s					
	Т					

## NON-PATENT DOCUMENTS

	NON-PATENT DOCUMENTO					
Г	*	1	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
$\vdash$						
		υ				
L						
Γ						
		<b>V</b>				
$\vdash$	$\dashv$					
l		w				
Γ						
	-	Х				
1						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.